Abstracts

Accurate Characterization of Cross-Over and Other Junction Discontinuities in Two-Layer Microstrip Circuits

A. Hoorfar, J.X. Zheng and D.C. Chang. "Accurate Characterization of Cross-Over and Other Junction Discontinuities in Two-Layer Microstrip Circuits." 1991 MTT-S International Microwave Symposium Digest 91.2 (1991 Vol. II [MWSYM]): 619-621.

A mixed-potential spatial-domain integral equation approach is used to model the coupling and junction effects when microstrip structures in two different layers of a common substrate are crossing each other. In particular, some canonical four port and three port junctions are characterized by applying a Galerkin method with linear basis functions for the currents.

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